

**Search Notes**

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EDMUND H. LEE

Applicant(s)/Patent under  
Reexamination

IWASAKI ET AL.

Art Unit

1791

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated	3/2/2009	EHL